Erratum: “A procedure to determine the optimum imaging parameters for atomic/molecular resolution frequency modulation atomic force microscopy”  [Rev. Sci. Instrum. 81, 093701 (2010)]

Author(s)
Hosokawa, Yoshihiro; Kobayashi, Kei; Oyabu, Noriaki; Matsushige, Kazumi; Yamada, Hirofumi

Citation
REVIEW OF SCIENTIFIC INSTRUMENTS (2011), 82(1)

Type
Journal Article

Copyright 2011 American Institute of Physics. This article may be downloaded for personal use only. Any other use requires prior permission of the author and the American Institute of Physics. The following article appeared in REVIEW OF SCIENTIFIC INSTRUMENTS 82, 019901 (2011) and may be found at http://link.aip.org/link/?rsi/82/019901
Erratum: “A procedure to determine the optimum imaging parameters for atomic/molecular resolution frequency modulation atomic force microscopy” [Rev. Sci. Instrum. 81, 093701 (2010)]
Yoshihiro Hosokawa, Kei Kobayashi, Noriaki Oyabu, Kazumi Matsushige, and Hirofumi Yamada

Citation: Rev. Sci. Instrum. 82, 019901 (2011); doi: 10.1063/1.3527911
View online: http://dx.doi.org/10.1063/1.3527911
View Table of Contents: http://rsi.aip.org/resource/1/RSINAK/v82/i1
Published by the American Institute of Physics.

Related Articles
Stochastic simulation of tip-sample interactions in atomic force microscopy
Improving the signal-to-noise ratio of high-speed contact mode atomic force microscopy
Contrast distortion induced by modulation voltage in scanning capacitance microscopy
Internal resonance based sensing in non-contact atomic force microscopy
Joint strength measurements of individual fiber-fiber bonds: An atomic force microscopy based method

Additional information on Rev. Sci. Instrum.
Journal Homepage: http://rsi.aip.org
Journal Information: http://rsi.aip.org/about/about_the_journal
Top downloads: http://rsi.aip.org/features/most_downloaded
Information for Authors: http://rsi.aip.org/authors
Erratum: “A procedure to determine the optimum imaging parameters for atomic/molecular resolution frequency modulation atomic force microscopy” [Rev. Sci. Instrum. 81, 093701 (2010)]

Yoshihiro Hosokawa,1 Kei Kobayashi,2 Noriaki Oyabu,1 Kazumi Matsushige,1 and Hirofumi Yamada1,a)

1Department of Electronic Science and Engineering, Kyoto University, Katsura, Kyoto 615-8510, Japan
2Office of Society-Academia Collaboration for Innovation, Kyoto University, Katsura, Kyoto 615-8520, Japan

(Received 16 November 2010; accepted 22 November 2010; published online 27 January 2011)

[doi:10.1063/1.3527911]

Equation (2) in the original article1 was incorrect. The correct equation should read

\[ \delta f(k, A) = \sqrt{\frac{f_0 k_B T B}{\pi k Q A^2}} + \frac{2n_{da}^2 B^3}{3A^2}. \]  

(2)

This correction does not affect any other contents of the original article.


a)Electronic mail: h-yamada@kuee.kyoto-u.ac.jp.